

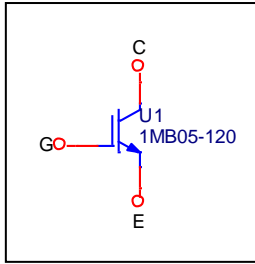
# Device Modeling Report

COMPONENTS: Insulated Gate Bipolar Transistor (IGBT)  
PART NUMBER: 1MB05-120  
MANUFACTURER: Fuji Electric



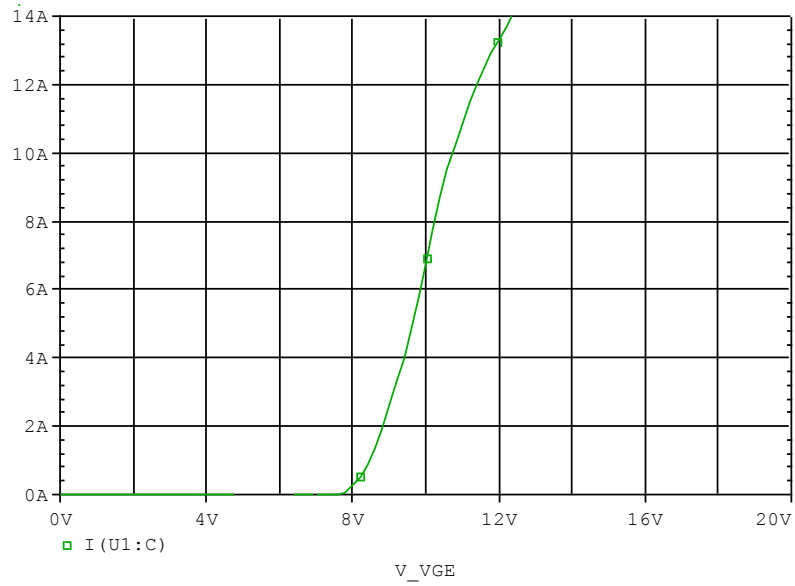
**Bee Technologies Inc.**

## Circuit Configuration

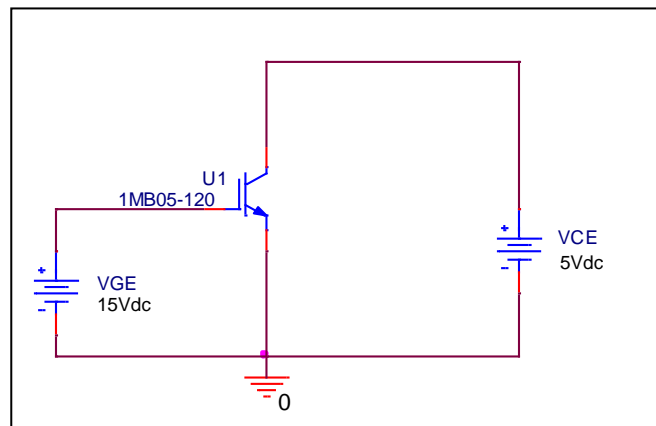


# Transfer Characteristics

## Circuit Simulation result

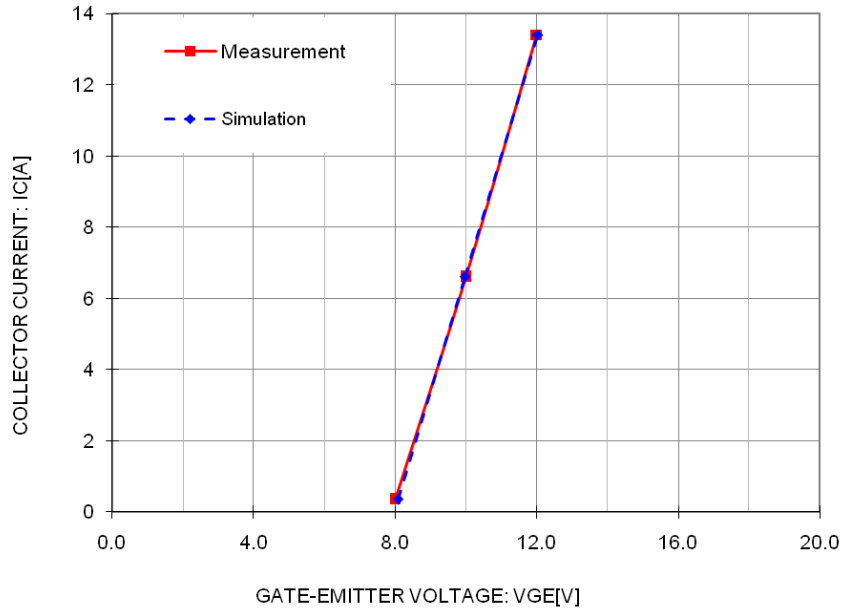


## Evaluation circuit



## Comparison Graph

### Simulation result



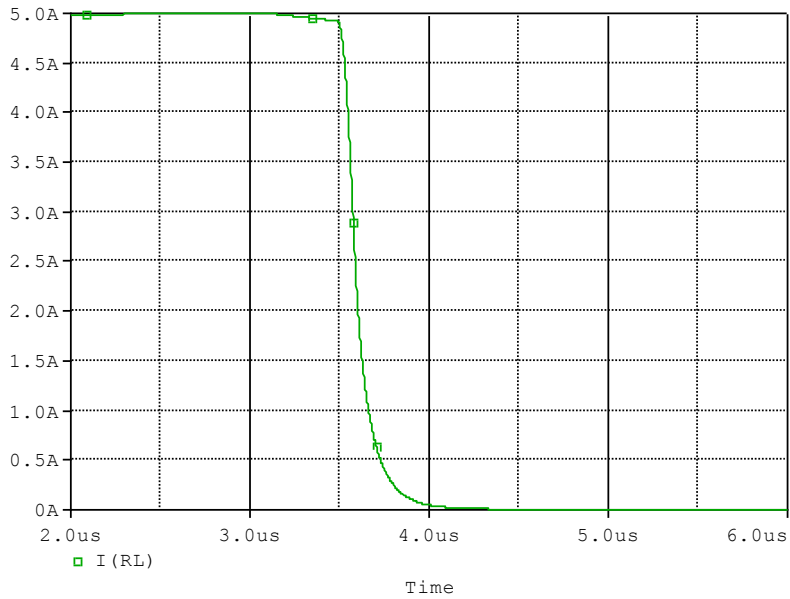
### Comparison table

Test condition:  $V_{CE} = 5$  (V)

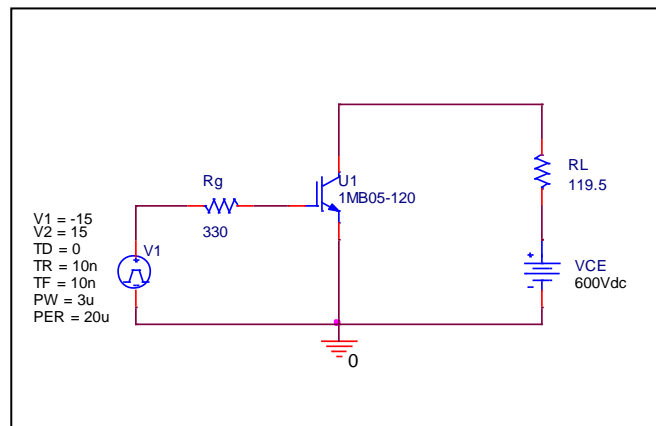
IC (A)	VGE (V)		%Error
	Measurement	Simulation	
0.350	8.000	8.082	1.02
6.600	10.000	9.970	-0.30
13.400	12.000	12.037	0.31

# Fall Time Characteristics

## Circuit Simulation result



## Evaluation circuit

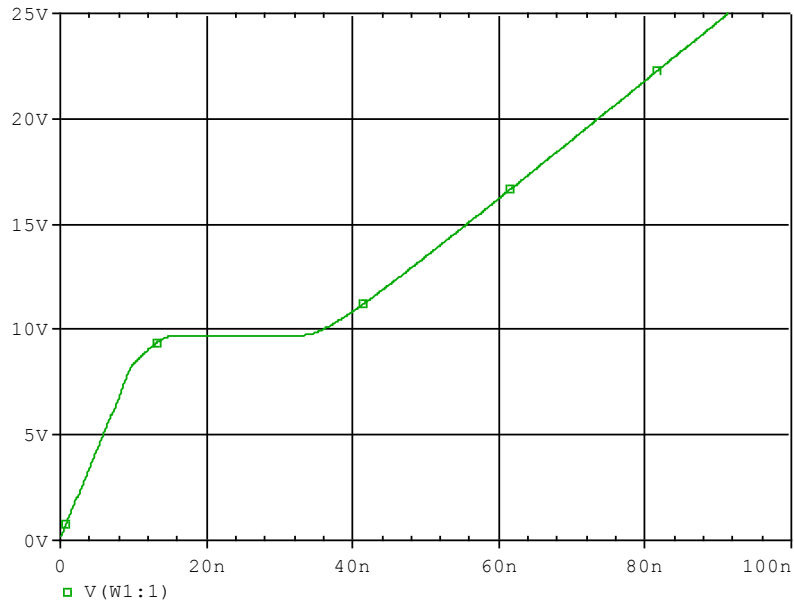


Test condition:  $I_C=5$  (A),  $V_{CC}=600$  (V)

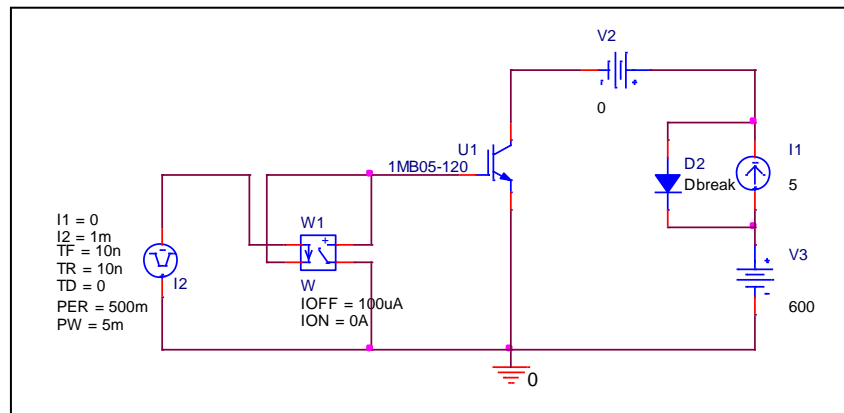
Parameter	Unit	Measurement	Simulation	%Error
tf	us	0.200	0.201	0.357

# Gate Charge Characteristics

## Circuit Simulation result



## Evaluation circuit

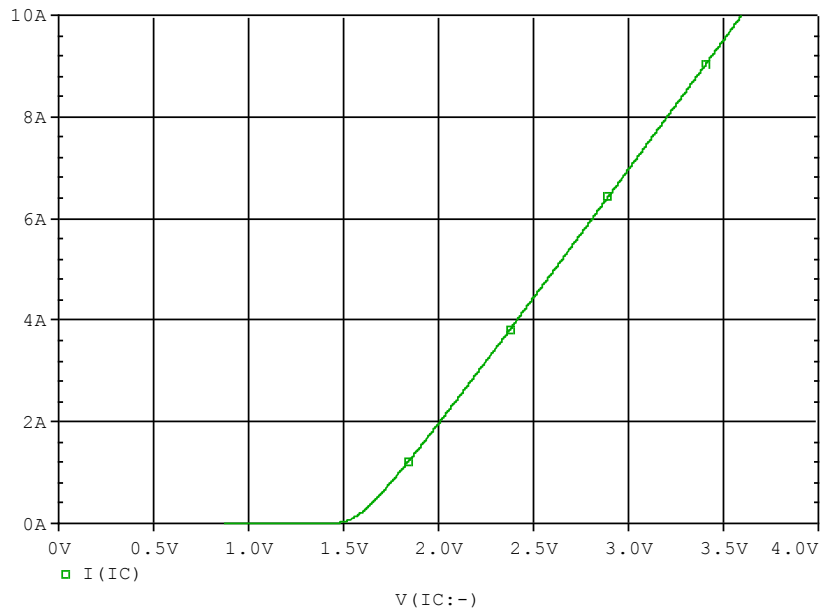


Test condition:  $V_{CC}=600$  (V),  $I_C=5$  (A),  $V_{GE}=15$  (V)

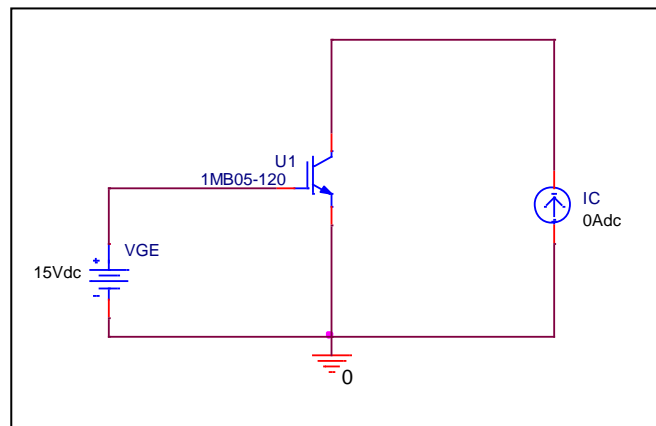
Parameter	Unit	Measurement	Simulation	%Error
<b>Qge</b>	<b>nc</b>	<b>12.000</b>	<b>12.000</b>	<b>0.000</b>
<b>Qgc</b>	<b>nc</b>	<b>26.000</b>	<b>25.565</b>	<b>-1.673</b>
<b>Qg</b>	<b>nc</b>	<b>55.000</b>	<b>55.623</b>	<b>1.133</b>

# Saturation Characteristics

## Circuit Simulation result

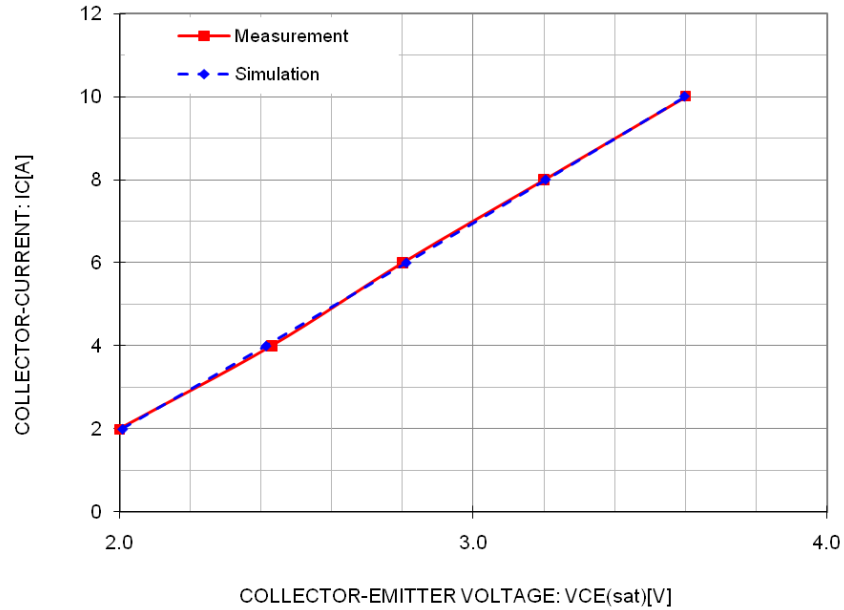


## Evaluation circuit



## Comparison Graph

### Simulation result



### Comparison table

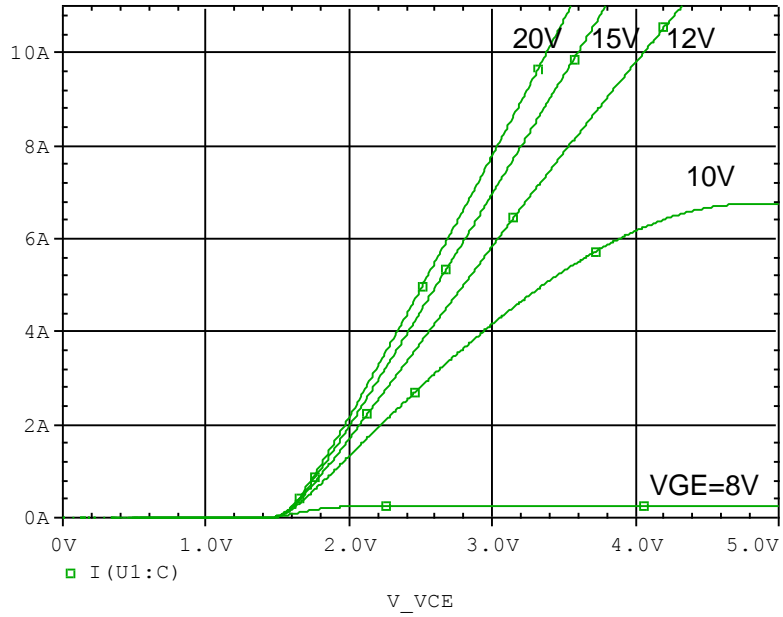
Test condition:  $V_{GE} = 15$  (V)

IF(A)	VF (V)		%Error
	Measurement	Simulation	
2.0	2.000	2.01	0.35
4.0	2.430	2.41	-0.71
6.0	2.800	2.81	0.35
8.0	3.200	3.20	0.12
10.0	3.600	3.60	-0.09



# Output Characteristics

## Circuit Simulation result



## Evaluation circuit

